# DIM800ECM33-F000



# **IGBT Chopper Module**

DS5815-1.2 January 2009(LN26568)

#### **FEATURES**

- Soft Punch Through Silicon
- Isolated AlSiC Base with AlN Substrates
- High Thermal Cycling Capability
- 10µs Short Circuit Withstand
- Lead Free construction

## **APPLICATIONS**

- Choppers
- Motor Controllers
- Power Supplies

The Powerline range of high power modules includes half bridge, chopper, dual, single and bi-directional switch configurations covering voltages from 1200V to 6500V and currents up to 3600A.

The DIM800ECM33-F000 is a 3300V, soft punch through n-channel enhancement mode, insulated gate bipolar transistor (IGBT) chopper module. The IGBT has a wide reverse bias safe operating area (RBSOA) plus 10us short circuit withstand. This device is optimised for traction drives and other applications requiring high thermal cycling capability.

The module incorporates an electrically isolated base plate and low inductance construction enabling circuit designers to optimise circuit layouts and utilise grounded heat sinks for safety.

### **ORDERING INFORMATION**

Order As:

#### DIM800ECM33-F000

Note: When ordering, please use the complete part number

### **KEY PARAMETERS**

V ces		3300V
V CE(sat) *	(typ)	2.8V
I c	(max)	<b>A008</b>
C(PK)	(max)	1600A

\*(measured at the auxiliary terminals)

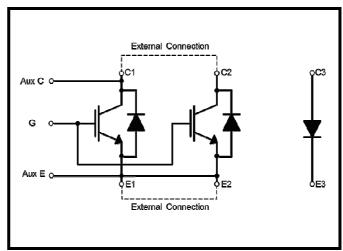


Fig. 1 Circuit configuration



Fig. 2 Package



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## **ABSOLUTE MAXIMUM RATINGS**

Stresses above those listed under 'Absolute Maximum Ratings' may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed. Exposure to Absolute Maximum Ratings may affect device reliability.

T<sub>case</sub> = 25° C unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
V <sub>CES</sub>	Collector-emitter voltage	V <sub>GE</sub> = 0V	3300	V
V <sub>GES</sub>	Gate-emitter voltage		±20	V
Ic	Continuous collector current	T <sub>case</sub> = 90 ° C	800	А
I <sub>C(PK)</sub>	Peak collector current	1ms, T <sub>case</sub> = 115 ° C	1600	Α
P <sub>max</sub>	Max. transistor power dissipation	T <sub>case</sub> = 25 ° C, T <sub>j</sub> = 150 ° C	10.4	kW
l <sup>2</sup> t	Diode I <sup>2</sup> t value	V <sub>R</sub> = 0V, t <sub>p</sub> = 10ms, T <sub>j</sub> = 125 °C	320	kA <sup>2</sup> s
V <sub>isol</sub>	Isolation voltage	Commoned terminals to base plate. AC RMS,1 min, 50Hz	6	kV
$Q_{PD}$	Partial discharge	IEC1287. V <sub>1</sub> = 3500V, V <sub>2</sub> = 2600V, 50Hz RMS	10	рС

#### THERMAL AND MECHANICAL RATINGS

Internal insulation material: AIN
Baseplate material: AISiC
Creepage distance: 29mm
Clearance: 20mm
CTI (Critical Tracking Index): 350

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
R <sub>th(j-c)</sub>	Thermal resistance – transistor both arms	Continuous dissipation - junction to case			12	° C/kW
R <sub>th(j-c)</sub>	Thermal resistance – diode, C3-E3 & transistor arms	Continuous dissipation - junction to case			24	° C/kW
R <sub>th(c-h)</sub>	Thermal resistance - case to heatsink (per module)	Mounting torque 5Nm (with mounting grease)			6	° C/kW
$T_j$	Junction temperature	Transistor			150	°C
		Diode			125	°C
T <sub>stg</sub>	Storage temperature range		-40		125	°C
	Screw torque	Mounting M6			5	Nm
		Electrical connections – M4			2	Nm
		Electrical connections – M8			10	Nm



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# **ELECTRICAL CHARACTERISTICS**

 $T_{case}$  = 25° C unless stated otherwise.

Symbol	Parameter	Test Conditions		Min	Тур.	Max	Units
I <sub>CES</sub>	Collector cut-off current	$V_{GE} = 0V, V_{CE} = V_{CES}$				4	mA
		V <sub>GE</sub> = 0V, V = V ,T <sub>case</sub> =125 °	, C			60	mA
I <sub>GES</sub>	Gate leakage current	$V_{GE} = \pm 15V, V_{CE} = 0V$				1	μА
V <sub>GE(TH)</sub>	Gate threshold voltage	$I_C = 80$ mA, $V_{GE} = V_{CE}$		5.5	6.5	7.0	V
V <sub>CE(sat)</sub> †	V <sub>CE(sat)</sub> <sup>†</sup> Collector-emitter saturation voltage	V <sub>GE</sub> = 15V, I <sub>C</sub> = 800A			2.8		V
, , , , , , , , , , , , , , , , , , , ,		$V_{GE} = 15V, I_{C} = 800A, T_{J} = 125$	°C		3.6		V
I <sub>F</sub>	Diode forward current	DC			800		Α
I <sub>FM</sub>	Diode maximum forward current	$t_p = 1 ms$			1600		Α
$V_F^{\dagger}$	V <sub>F</sub> <sup>†</sup> Diode forward voltage	I <sub>F</sub> = 800A			2.9		V
		I <sub>F</sub> = 800A, T <sub>J</sub> = 125 °C			3.0		V
C <sub>ies</sub>	Input capacitance	$V_{CE} = 25V, V_{GE} = 0V, f = 1MHz$			144		nF
C <sub>res</sub>	Reverse transfer capacitance	$V_{CE} = 25V, V_{GE} = 0V, f = 1MHz$			2.2		nF
L <sub>M</sub>	Module inductance				15		nΗ
R <sub>INT</sub>	Internal resistance				135		μΩ
SC <sub>Data</sub>	Short circuit current, I <sub>SC</sub>	$T_j = 125$ ° C, $V_{CC} = 2500$ V $V_{GE} \le 15$ V, $t_p \le 10\mu$ s,	I <sub>1</sub>		4000		Α
		$V_{CE(max)} \le V_{CES} - L^* x di/dt$ IEC 6074-9	l <sub>2</sub>		3700		Α

 $<sup>\</sup>ensuremath{^{\dagger}}\xspace Measured at the auxiliary terminals <math display="inline">\ensuremath{^{\dot{}}}\xspace L$  is the circuit inductance +  $L_M$ 



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# **ELECTRICAL CHARACTERISTICS**

T<sub>case</sub> = 25 ° C unless stated otherwise

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
$t_{\text{d(off)}}$	Turn-off delay time	I <sub>C</sub> = 800A		3.0		μS
t <sub>f</sub>	Fall time	V <sub>GE</sub> = ±15V		270		ns
E <sub>OFF</sub>	Turn-off energy loss	V <sub>CE</sub> = 1800V		1050		mJ
t <sub>d(on)</sub>	Turn-on delay time	$R_{G(ON)}=3.9\Omega,~R_{G(OFF)}=6.2\Omega$		1.3		μS
t <sub>r</sub>	Rise time	C <sub>ge</sub> = 220nF, L ~ 100nH		275		ns
E <sub>ON</sub>	Turn-on energy loss	$\begin{split} I_{C} = 800\text{A},  V_{GE} = \pm 15\text{V},  V_{CE} = 1800\text{V}, \\ R_{G(ON)} = 2.7\Omega,  C_{ge} = 220\text{nF},  L \sim &100\text{nH} \end{split}$		1250		mJ
$Q_g$	Gate charge			20		μС
Q <sub>rr</sub>	Diode reverse recovery charge	I <sub>F</sub> =800A		320		μС
l <sub>rr</sub>	Diode reverse recovery current	V <sub>CE</sub> =1800V		670		Α
E <sub>rec</sub>	Diode reverse recovery energy	dI <sub>F</sub> /dt =4000A/us		300		mJ

T<sub>case</sub> = 125 ° C unless stated otherwise

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
t <sub>d(off)</sub>	Turn-off delay time	I <sub>C</sub> = 800A		3.1		μs
t <sub>f</sub>	Fall time	$V_{GE} = \pm 15V$		280		ns
E <sub>OFF</sub>	Turn-off energy loss	V <sub>CE</sub> = 1800V		1200		mJ
$t_{d(on)}$	Turn-on delay time	$R_{G(ON)}=3.9\Omega,\ R_{G(OFF)}=6.2\Omega$		1.2		μs
t <sub>r</sub>	Rise time	C <sub>ge</sub> = 220nF, L ~ 100nH		315		ns
E <sub>ON</sub>	Turn-on energy loss	$ \begin{array}{c} I_{C} = 800 A, \ V_{GE} = \pm 15 V, \ V_{CE} = 1800 V, \\ R_{G(ON)} = 2.7 \Omega, \ C_{ge} = 220 nF, \ L \sim 100 nH \end{array} $		1750		mJ
$Q_{rr}$	Diode reverse recovery charge	I <sub>F</sub> =800A		600		μС
I <sub>rr</sub>	Diode reverse recovery current	V <sub>CE</sub> =1800V		800		Α
E <sub>rec</sub>	Diode reverse recovery energy	dI <sub>F</sub> /dt =4000A/us		600		mJ



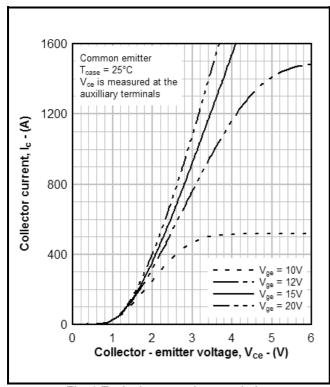


Fig. 3 Typical output characteristics

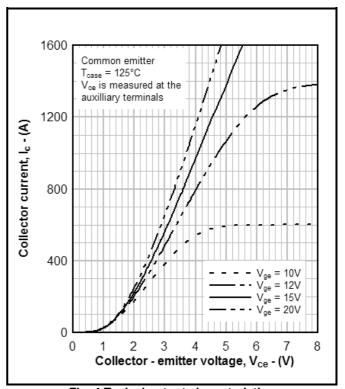


Fig. 4 Typical output characteristics

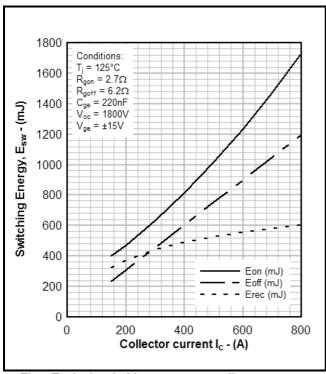


Fig.5 Typical switching energy vs collector current

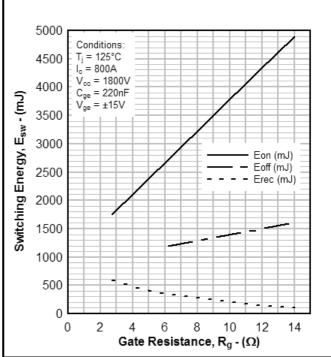
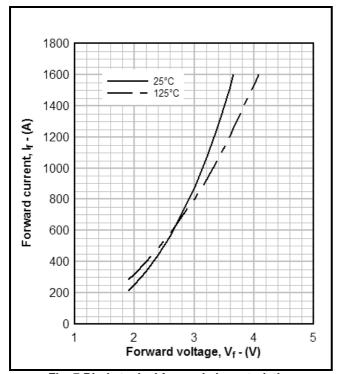


Fig. 6 Typical switching energy vs gate resistance

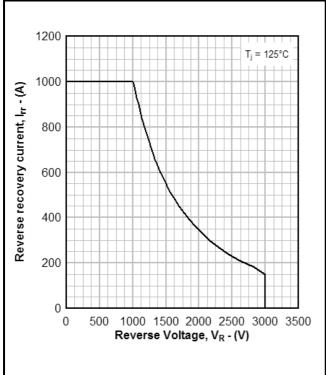


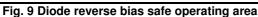


1800 1600 Module 1400 Chip Collector current, I<sub>c</sub> - (A) 1200 1000 800 600 Conditions: 400 T<sub>case</sub> = 125°C  $V_{ge} = \pm 15V$ 200  $R_{goff} = 6.2\Omega$ C<sub>ge</sub> = 220nF 0 500 1000 1500 2000 2500 3000 0 Collector emitter voltage, V<sub>ce</sub> - (V)

Fig. 7 Diode typical forward characteristics

Fig. 8 Reverse bias safe operating area





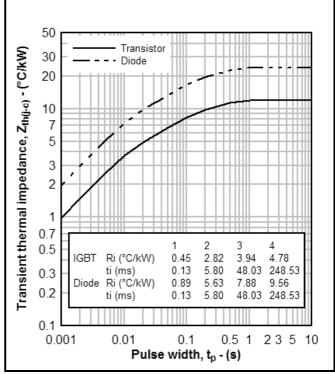
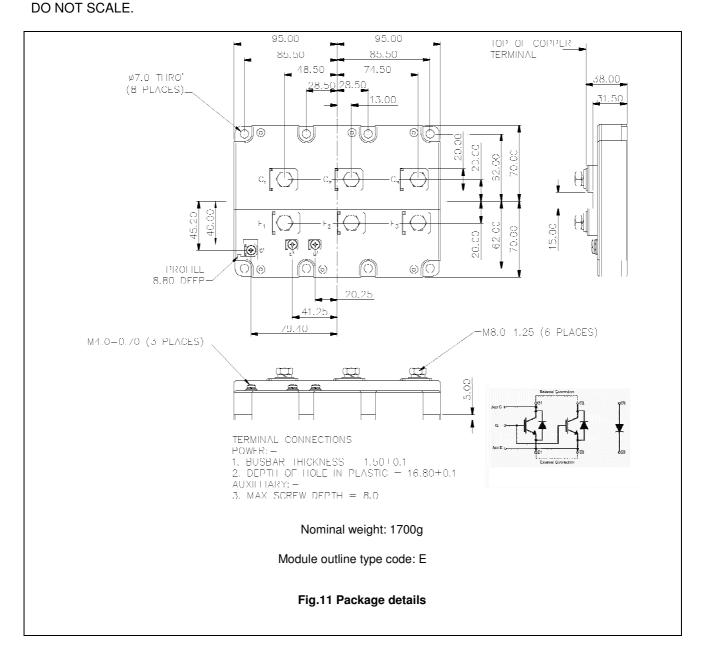


Fig. 10 Transient thermal impedance



#### **PACKAGE DETAILS**

For further package information, please visit our website or contact Customer Services. All dimensions in mm, unless stated otherwise.





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The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

#### **HEATSINKS**

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.



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